## M agnetic im aging of the param agnetic M eissner e ect in the granular high-T<sub>c</sub> superconductor B $i_2$ Sr<sub>2</sub>C aC u<sub>2</sub>O x

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We have in aged the spatial distribution of magnetic ux on a granular sam ple of the high-tem perature superconductor  $Bi_2Sr_2CaCu_2O_x$  using a scanning SQUID microscope. Our results establish the presence of spontaneous orbital magnetic moments which were suggested to be the origin of the paramagnetic response of these materials. The signature of the orbital magnetic moments is a rather broad distribution of local magnetic elds at the surface of the sam ple. A sim ple model for the distribution is presented.

C onventional superconductors generally tend to expel a smallexternalmagnetic eld upon cooling into the superconducting state. This M eissner e ect leads to com plete, or (due to rem nant trapped ux, e.g. in a ceram ic sam ple com posed of grains and voids) partial, diam agnetism. Therefore it came as a surprise when a param aqnetic signal was observed in ceram ic B  $i_2$  Sr<sub>2</sub>C aC u<sub>2</sub>O x (B i-2212)<sup>1{4</sup>. The origin of the param agnetism has been a controversial subject. Braunisch et al.4 and Kusmartsev<sup>5</sup> proposed that some form of spontaneous orbital currents were responsible, giving rise to magnetic moments which could be aligned by the external eld. This proposal for spontaneous orbital currents (W ohlleben Effect) in turn led two of us<sup>6;7</sup> to propose that an intrinsic  $d_{x^2}$   $v^2$  -wave symmetry of the superconducting state would naturally lead to frustrated Josephson junction circuits in a ceram ic sample where random ly oriented grains contact each other8. A lthough spontaneous orbital currents have now been unequivocally dem onstrated for high-tem perature superconductors in controlled geom etries, and the evidence for  $d_{x^2 \ y^2}$  -w ave sym m etry is now overwhelm ing<sup>9 {15</sup>, the controversy has continued. In part this is due to the observation of param agnetic signals under quite di erent conditions, e.g. in bulk Nb samples<sup>16{19</sup>. In this letter we report the rst direct imaging of the local magnetic ux distribution in the ceram ics by a scanning SQUID m icroscope (SSM) and demonstrate that a polarization of the distribution of spontaneous uxes is indeed responsible for the param agnetic signal.

Before proceeding to a discussion of our experiment we would like to remark that these two forms of paramagnetism in ceramic Bi-2212 and in bulk Nb sample can be clearly distinguished in several other ways. For example, the cooling rate a ects the magnetic response di erently in the two cases. Recent experimental data show signi cant di erences between Nb and granular

 $B_{1/2}Sr_2CaCu_2O_x$  (Bi2212) samples. While slow cooling enhances the param agnetic signal for the granular sam ple, it is dim inished in the Nb sample. This clearly indicates that the equilibrium state of both samples in a small magnetic eld is quite di erent<sup>20</sup>. For the Nbdisks K oshelev and Larkin gave an explanation based on the idea that during the cooling process the surface region nucleates superconductivity before the bulk, so that magnetic ux in the sample is compressed and creates an enhanced magnetization<sup>21</sup>. This compressed ux mechanism leads to a metastable state which depends on the cooling procedure whereas the polarization of the spontaneous orbitalm om ents is an equilibrium process. Further, noise m easurem ents of the m agnetization of B i2212 give signals which are compatible with the presence of spontaneous orbitalm om  $ents^{22}$ .

We used a sample whose preparation, characterization and measurement of the magnetization were reported previously<sup>4</sup>. The magnetic images were made with a high-resolution SSM<sup>23</sup>. This instrument uses a Nb-A 1,0 3-Nb low T C SQUID fabricated on a silicon substrate. The substrate is polished to a sharp tip spaced a few tens of m icrons from a well-shielded superconducting pickup loop, which is an integral part of the SQUID. The SQUD substrate is mounted on a exible cantilever, oriented at a shallow angle, typically 20 degrees relative to the sam ple surface, and the sam ple is scanned relative to the SQUD, with the tip of the substrate in direct contact with the sample. For these measurem ents the sample was polished to a mirror nish, and both sample and SQUID were coated with a thin layer to protect the SQUID substrate from abrasion. We estimate, from ts of A brikosov vortices in aged using sim ilar tip geom etry and SQUID and sam ple coating techniques, that the spacing between the pickup loop and the surface of the superconducting sample is about 5 m. The SQUID signal is proportional to the magnetic ux through the loop area. The present im ages were taken with a square pickup loop. In this geometry a single bulk Abrikosov vortex couples about  $0.5_{0}$  ( $_{0}$  = h=2e) through the 8.2 m 82 m area of the pickup loop located directly above it.

The Fig. 1 (a-f) shows a series of SSM in ages of the Bi2212 sample which was cooled through the superconducting transition temperature ( 84K) at di erent values of an externally applied magnetic eld. The in ages were taken with the eld still applied and the sample and SQUID immersed in liquid helium at 42K. Each in age

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is of a square area 3mm on a side. The outlined square shows the 480 m 480 m area of the images used to generate the histogram s of Fig 2. We analyze only this area, because our SQ U D has twom agnetic eld sensitive regions: the pickup bop, and the hole in the superconducting ground plane for the ux modulation  $coil^{23;24}$ . The images were taken with the SQ U D oriented vertically, with the pickup bop towards the top of the images. Therefore, when the pickup bop covers the region outlined, them odulation hole senses areas wello the sam ple (below the bottom of the image), and simply contributes a constant background signal to the image.

In Fig.1 we show the spatial distribution of the magnetic ux in and around the sam ple. The grey contrast scale is chosen so that white corresponds to the largest and black to the smallest (often negative) ux value. In all cases the ux is plotted relative to the ux introduced by the external eld, which sets the grey levelaw ay from the sam ple. One overall feature observable by eye is the di erence between the param agnetic m agnetization (sam ple is brighter than the background) at weak elds, and a diam agnetic signal (sam ple is darker than the background), in the pickup loop at strong elds. For weak external elds the inhom ogeneity of the m agnetic ux is clearly visible and gives rise to a broad distribution of the local uxes.

The ux distributions relative to the external ux m easured in the outlined square are shown as histograms in Fig. 2. The distribution is broad, as anticipated above, and the average value indicates the overall response, which is paramagnetic for weak elds. In Tab.1 we list the average ux  $_{\rm av}$  ext and the standard deviation =  $h(_{\rm av})^2 i^{1-2}$  (ext denotes the ux of the external eld through the pickup loop).

We rst compare our SSM data with the totalm agnetization m easurem ent of the whole sam ple4. Both show the same qualitative dependence of the low-tem perature magnetization on the applied eld (see Fig.3). In particular, the sign of the magnetization changes for both m easurements at the same eld value B  $_{\rm ext}$  0.6G. This con m s that the SSM data, scanning only a part of the sam ple, is typical of the m agnetization of the whole sam ple. Let us now turn to the width of the ux distribution, i.e. the standard deviation from the average ux. The eld dependence of indicates the existence of spontaneous ux at low external elds. If the ux observed were entirely due to ux trapped and com pressed between and inside the grains, then we expect that both <sub>av</sub> and would tend to zero in the zero-eld lim it. This is, however, not the case as we illustrate in Fig.3, where we observe that the zero-eld lim it of is nite. This can be readily interpreted if we assume that the ux distribution at low elds is mostly due to spontaneous orbital currents for low external elds, which can ow in either direction. Thus we expect to see an inhom ogeneous eld pattern even at zero external eld. The broadening of the ux distribution with increasing eld can be understood as due to ux trapping and M eissner e ect of the grains.

G enerally more magnetic ux concentrates in the voids and essentially little ux is trapped inside the grains. This leads to a enhancement of the contrast in the ux values for large external elds and, consequently, to a broader distribution.

For the low-eld regime the ux distribution can be easily simulated using a model for the boundary between m any grains. Such a grain boundary can be considered as a long Josephson junction and m ay be described by a Sine-G ordon equation<sup>25</sup>,

$$\frac{e^{2'}}{e^{2'}} = \frac{1}{\frac{2}{\pi}} \sin (' (x) + (x)); \qquad (1)$$

where ' is the Josephson phase di erence on the grain boundary and J is the Josephson penetration depth. The presence of 0- and -junctions enters through (x), which assumes the values 0 or as a function of the position x along the grain boundary. This model is sim ulated on a system of length L using N mesh points to determine '(n) for xed values of  $(n)^{26}$ . The local ux (n) between m esh point n and n 1 is given by  $_0$  ('(n) '(n 1))=2. The external eld is in-(n) = troduced via the boundary conditions at the two ends of the junction (' (N ) ' (N 1))=2 = (' (2) ' (1))=2 =  $B_{ext}L=N_0$ . Using a relaxation m ethod<sup>26</sup>, we calculate ' while gradually low ering the tem perature by introducing decreasing values of  $_{\rm J}$ . In Fig.4 we show the ux distribution obtained for the case of L = 100, N = 1000, starting with  $_{\rm J}$  = 40, which is decreased by successive division by 2 to a nalvalue of 0.156. The low external eld is  $B_{ext} = 0:1_{0} = Ld$  (d is the magnetic width of the junction). We get a broad distribution with a shape that is qualitatively similar to the experiment. The phase ' has essentially a random walk like dependence on x so that the histogram has an approximately Gaussian distribution. W ithin this simple model we can describe the generation of spontaneous ux and the interaction e ects between ux lines. However, the broadening of the ux distribution with increasing eld is not properly reproduced because the contrast between trapped ux and the screening grains is not taken into account.

In sum m ary we would like to emphasize that the loweld data obtained by an SSM on a granular Bi2212 sample are in very good qualitative agreement with the previous m agnetization m easurem ents and, in addition, provide direct evidence for the presence of spontaneous orbital currents. On the other hand, independent evidence<sup>20;22</sup> indicates that the param agnetic signal in Nb samples has a di erent mechanism, likely the one proposed by Koshelev and Larkin<sup>21</sup>. It is not possible from this SSM measurement alone to determine the origin of the orbital currents. However, a series of previous experiments suggest strongly that grain boundaries with intrinsic -phase shifts are appearing in these hightem perature superconductors and are very likely responsible for the param agnetic response  $9^{\{15\}}$ . In this sense, the param agnetic response (W ohlleben e ect) in granular B i2212 system s is consistent in all aspects with an explanation based on  $d_{x^2-y^2}$ -wave pairing symmetry<sup>6;7;27</sup>.

W e are very grateful to the late D.W ohlleben for attracting our attention to this e ect and for providing us with a sample produced by members of his group. W e would also like to thank M B.K etchen, M.Bhushan, and A W. Ellis for assistance in the design and fabrication of the microscope used in this work, and K A.M oler and D J. Scalapino for assistance in the developm ent of the computer program used for the simulation presented here. This work was supported by the Swiss Nationalfonds.

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FIG.1. Scanning SQUID m icroscope in ages of a granular Bi2212 sample, cooled and in aged in various elds. Each im age has 512x512 pixels, with 6 m icrons per pixel. The individual in ages are labeled by the cooling eld, and by the m axim alrange of variation of the ux (in units of  $_0$ ) in each case. The outlined areas are regions of the in ages analyzed further in the histogram s of Fig.2.

FIG.2. H istogram s of the distribution of occurrence of each SQUID ux value in the outlined areas of Fig.1, norm alized so that the integral yields unity. Each panel is labeled by the cooling eld in G auss. The horizontal axes correspond to the ux through the SQUID at a particular spot on the sam ple, relative to the background with the pickup loop far from the sam ple, i.e. ext.

FIG. 3. Standard deviation of the ux distribution =  $h(a_v)^2 i^{1=2}$  (circles, solid line) as a function of the external eld. The average ux  $a_v$  of the SSM m easurement (diam onds, long dashed line) com pares well with the appropriately scaled m agnetization of the whole sam ple (x, dashed line).<sup>4</sup>

FIG. 4. Histogram for the small eld limit of the Sine-Gordon model described in the text.

TABLE I. A verage ux  $_{av} = h$   $_{ext}$  in easured in the SSM and standard deviation  $= h(a_{av})^2 i^{1-2}$  for dievent applied elds.

H <sub>ext</sub>	av= 0	= 0
10 m O e	0.0157	0.0384
30 m O e	0.0128	0.0386
100 m O e	0.0299	0.0494
300 m O e	0.0318	0.0675
10e	-0.0676	0.139
30e	-0.51	0.465







